

<b>Notice of References Cited</b>	Application/Control No. 10/720,058	Applicant(s)/Patent Under Reexamination FANG ET AL.	
	Examiner Christopher M. Raabe	Art Unit 2879	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2001/0002279	05-2001	Forrest et al.	427/255.26
	B	US-2002/0160553	10-2002	Yamanaka et al.	438/149
	C	US-2002/0098378	07-2002	Kim et al.	428/690
	D	US-6,402,579	06-2002	Pichler et al.	445/24
	E	US-5,998,803	12-1999	Forrest et al.	257/40
	F	US-2002/0157596	10-2002	Stockman et al.	117/2
	G	US-2003/0030059	02-2003	Shi et al.	257/79
	H	US-2003/0018097	01-2003	O'Neill et al.	522/1
	I	US-2002/0070385	06-2002	Yamagata, Hirokazu	257/93
	J	US-5,874,803	02-1999	Garbuzov et al.	313/506
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.